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F rm PTO-1 (Rev. 8-83)	•	U.S. epartment of Commerce Patent and Trademark Office		Atty Docket 0756-229		Serial No. 09/837,877	
'INTONNATION DISCLOSURE STATEMENT			Applicants: Shunpei YAMAZAKI et al.				
	APR 1 5 2002 😸		Filing Date: April 19, 2001		Group Art Unit: N/A		
\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\	E S	FOREIGN PATEN	IT DOCUMENTS				
Examiner Initial	PRADE NO Scument Number	Date	Country	Class	Subclass	Translation Yes No	
MC	11-354802	12/24/1999	JP			Full Eng	
		-		•	<u> </u>		

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Examiner,

Date Considered

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this formwith next communication to applicant.

Form PTO-14 (Rev. 8-83)		epartment of Commerce nt and Trademark Office	Atty Docket 0756	-2	Serial No. 0	9/837,877
METATION DISCLOSURE STATEMENT			Applicants: Shunpei YAMAZAKI et al.			
Mile 1 3 20 ²³		Filing Date: April 19, 2001		Group Art Unit: Not		
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Examiner Initial	TA TRADE Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
M	4,609,930	09/02/1986	Yamazaki			
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MC	4,984,033	01/08/1991	Ishizu et al.			
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INFORMATION DISCLOSURE STATEMENT		Applicants: Shunpei YAMAZAKI et al.						
		Filing Date: April 19, 2001		Group Art Unit: Not				
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	02-015676	01/19/1990	JP			Eng Abst		
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